# **RAM Verification Plan**

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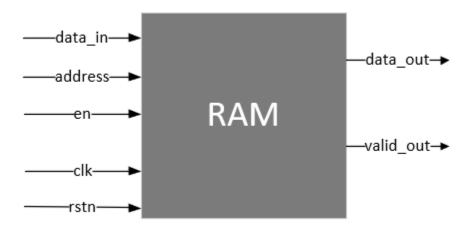
### 1. Introduction

#### **Overview:**

This document outlines the verification process for Random-Access Memory (RAM) design. It describes the design functionality, verification strategy, test-cases, coverage results, and exit criteria.

### 2. Design Details

- **Description:** RAM is a synchronous single port memory block that supports read and write operations. It is used to store data based on a specified address.
- IO Ports:



Port Name	Direction	Width	Active	Description
clk	Input	1	NA	Clock signal
rstn	Input	1	Low	Asynchronous reset
data_in	Input	32	NA	Data to be written into the memory when en is high.
en	Input	1	High	Write enable. If high, data is written to RAM. If low, data is read out.
address	Input	4	NA	Address for both write and read operations.
data_out	Output	32	NA	Data read from the RAM when en is low.
valid_out	Output	1	High	Valid signal indicates data_out is valid and can be read.

#### • Latency:

Write Operation: 0 clock cycle. Read Operation: 1 clock cycle.

### 3. Verification Strategy

• **Methodology:** UVM verification.

### 4. Exit Criteria

Metric	Target Value
Functional Coverage	100%
Code Coverage	100%
Number of bugs	0

#### 5. Test Items

- 1. Reset behavior.
  - Verify all the outputs are zero when reset.
- 2. Write-Read.
- 3. Write-Read at the lowest address.
- 4. Write-Read at the highest address.
- 5. Back-to-Back Write-Read for Full Memory.
- 6. Back-to-Back Write-Write-Read for Full Memory.
- 7. Back-to-Back Write-Read-Read for Full Memory.
- 8. Write-Read all-zero pattern.
- 9. Write-Read all-one pattern.
- 10. Write-Read one-zero pattern.
- 11. Reset-Read to check data is unchanged.
- 12. Random writes, reads and resets until 100% functional coverage.

### 6. Test Case Table

<b>Test Case ID</b>	Feature Verified	Status
1	Reset behavior	Pass
2	Write operation	Pass
3	Write-Read at the lowest address	Pass
4	Write-Read at the highest address	Pass
5	Back-to-Back Write-Read	Pass
6	Back-to-Back Write-Write-Read	Pass
7	Back-to-Back Write-Read-Read	Pass
8	Write-Read all-zero pattern	Pass
9	Write-Read all-one pattern	Pass
10	Write-Read one-zero pattern	Pass

11	Reset-Read to check data is unchanged	Pass
12	Random writes, reads and resets	Pass

# 7. Traceability Matrix

Test Item	rst	en	addr	Data_in	Data_out	expected output
Reset behavior	✓	×	×	×	✓	Data_out = 0
Write operation	×	<b>√</b>	<b>√</b>	✓	×	NA
Write-Read at the lowest address	×	<b>√</b> / <b>×</b>	✓	<b>√</b>	✓	Data_out = Data_in
Write-Read at the highest address	×	<b>√</b> / <b>×</b>	✓	<b>√</b>	✓	Data_out = Data_in
Back-to-Back Write-Read	×	<b>√</b> / <b>×</b>	<b>√</b>	<b>√</b>	<b>√</b>	Data_out = last Data_in
Back-to-Back Write-Write-Read	×	<b>√</b>	<b>√</b>	<b>√</b>	<b>✓</b>	Data_out = 2nd Data_in
Back-to-Back Write-Read-Read	×	<b>√</b> / <b>×</b>	<b>√</b>	<b>√</b>	<b>√</b>	repeated Data_out
Write-Read all-zero pattern	×	<b>√</b> / <b>X</b>	<b>√</b>	0	<b>√</b>	Data_out = 0
Write-Read all-one pattern	×	<b>√</b> / <b>×</b>	<b>√</b>	all 1s	✓	Data_out = all 1s
Write-Read one- zero pattern	×	<b>√</b> / <b>×</b>	<b>√</b>	10101	✓	Data_out = 10101
Reset-Read to check data is unchanged	✓	×	✓	×	✓	Data_out = before reset

## 8. Coverage Results

Coverage Type	Percentage
Functional Coverage	100%
Code Coverage	100%

## 9. Open Issues

Bug ID	Description	Severity	Status	Owner
#1	NA	NA	NA	NA